



Universität
Basel

Publication

Atomic force microscopy

JournalArticle (Originalarbeit in einer wissenschaftlichen Zeitschrift)

ID 171263

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Year 1992

Title Atomic force microscopy

Journal Progress In Surface Science

Volume 41

Number 1

Pages / Article-Number 3-49

The basic principles of atomic force microscopy are discussed. Various deflection sensors are described and compared with each other. A simple theoretical basis of the fundamental forces, such as van der Waals, electrostatic, magnetic, capillary, ionic repulsion and frictional forces, is given and the relevant experimental work is summarized.

Publisher Elsevier

ISSN/ISBN 0079-6816

edoc-URL <http://edoc.unibas.ch/dok/A5839511>

Full Text on edoc No;

Digital Object Identifier DOI 10.1016/0079-6816(92)90009-7

ISI-Number WOS:A1992JX80900001

Document type (ISI) Review